

# GLAST Prototype SMD/98

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Size: 6.4 x 6.4 cm<sup>2</sup>  
Thickness: 385 μm  
Channels: 320

- 1) Total samples: 57 ( $I_{leak} < 50\text{nA/cm}^2$ )  
56 ( $I_{leak} < 10\text{nA/cm}^2$ )

## 2) Dead Channel:

<u>No. of Sensors</u>	<u>Status</u>	<u>%</u>
51 (89%)	Perfect	
2 (3.5%)	1 channel pin hole	0.3%
1 (1.8%)	1 channel Al open	0.3%
1 (1.8%)	1 bypath Al open	0.3%

(capacitor:OK)

Total dead channel rate =  $1.7 \times 10^{-4}$

2 >3 channels (Thrown away or?)

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## Leakage Current ( $\text{nA}/\text{cm}^2$ )

